

### HFS10N80-VB Datasheet

# N-Channel 800V (D-S) Super Junction Power MOSFET

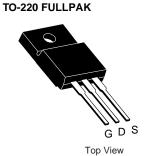
PRODUCT SUMMARY						
V <sub>DS</sub> (V) at T <sub>J</sub> max.	800	)				
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.85				
Q <sub>g</sub> max. (nC)	20					
Q <sub>gs</sub> (nC)	2.4					
Q <sub>gd</sub> (nC)	11					
Configuration	Single					

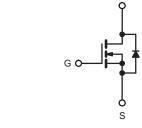
#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (C<sub>iss</sub>)
- · Reduced switching and conduction losses
- Ultra low gate charge (Qq)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)							
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V <sub>DS</sub>	800	V		
Gate-Source Voltage			$V_{GS}$	± 30	\ \ \		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V at 10 V	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	7			
	V <sub>GS</sub> at 10 V	$T_C = 25 ^{\circ}\text{C}$ $T_C = 100 ^{\circ}\text{C}$		5.9	А		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	11	1		
Linear Derating Factor				1.89/1.6/0.4	W/°C		
Single Pulse Avalanche Energy b			E <sub>AS</sub>	86	mJ		
Maximum Power Dissipation			$P_{D}$	99/97/46	W		
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt 50		V/ns		
Reverse Diode dV/dt <sup>d</sup>		αν/αι	3.2	V/115			
Soldering Recommendations (Peak Temperature) c	for	10 s		300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.5 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ ,  $dI/dt = 100 \text{ A/}\mu\text{s}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ .



THERMAL RESISTANCE RATI	NGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	72	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.7	G/VV

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static				1	<u> </u>		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	800	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2	-	4	V
			V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	$I_{GSS}$		V <sub>GS</sub> = ± 30 V	-	-	± 1	μA
	_	V <sub>DS</sub> =	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$		-	1	
Zero Gate Voltage Drain Current	$I_{DSS}$	V <sub>DS</sub> = 520 \	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4 A	-	0.85	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	s = 30 V, I <sub>D</sub> = 4 A	-	19	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$ ,		-	373	_	
Output Capacitance	C <sub>oss</sub>	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$		26	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	1	f = 1 MHz	-	14	-	1
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	46	-	pF
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	64	-	
Total Gate Charge	Qg			-	26		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 4 A, V_{DS} = 520 V$	-	2.1	-	nC
Gate-Drain Charge	$Q_{gd}$			-	2.8	-	
Turn-On Delay Time	t <sub>d(on)</sub>			-	26	-	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 4 A,		-	55.7	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		$V_{GS} = 320 \text{ V}, \ T_{G} = 4 \text{ A},$ $V_{GS} = 10 \text{ V}, \ R_{g} = 9.1 \Omega$		71	-	113
Fall Time	t <sub>f</sub>			-	41	-	
Gate Input Resistance	$R_g$	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	S	·					
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	A
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	18	
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V		-	-	1.4	V
Reverse Recovery Time	t <sub>rr</sub>			-	192	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = I_S = 4 \text{ A},$ $dI/dt = 100 \text{ A/µs}, V_R = 400 \text{ V}$		-	2.4	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			_	11	_	Α

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

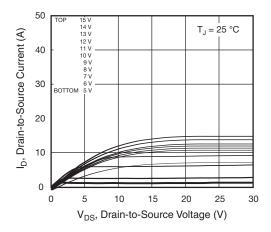


Fig. 1 - Typical Output Characteristics

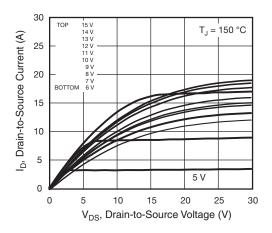


Fig. 2 - Typical Output Characteristics

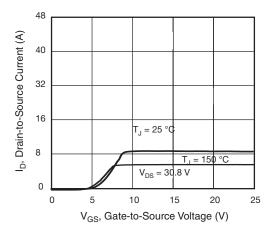


Fig. 3 - Typical Transfer Characteristics

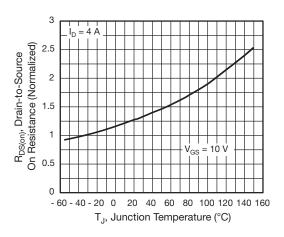


Fig. 4 - Normalized On-Resistance vs. Temperature

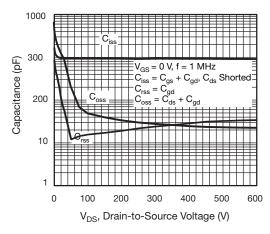


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

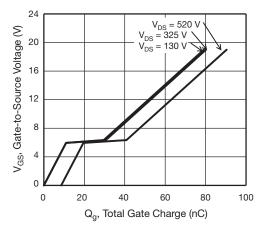


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



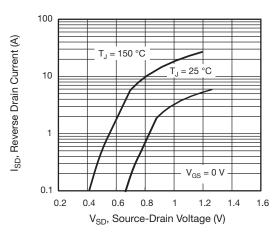


Fig. 7 - Typical Source-Drain Diode Forward Voltage

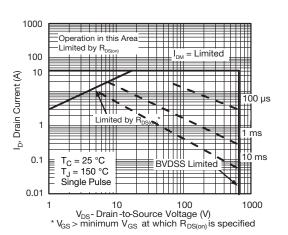


Fig. 8 - Maximum Safe Operating Area

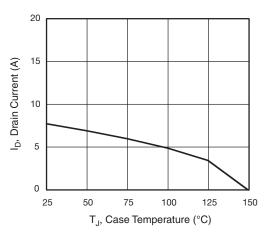


Fig. 9 - Maximum Drain Current vs. Case Temperature

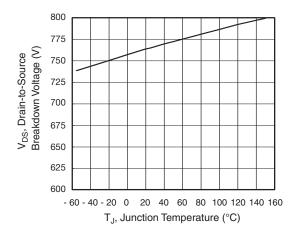


Fig. 10 - Temperature vs. Drain-to-Source Voltage

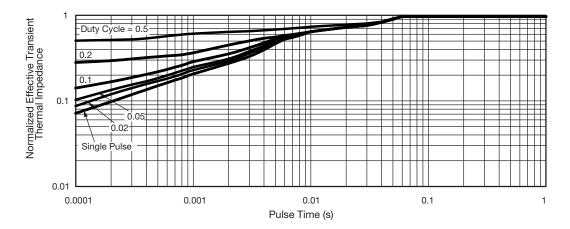


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



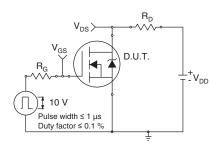


Fig. 12 - Switching Time Test Circuit

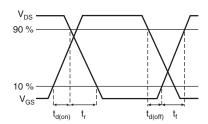


Fig. 13 - Switching Time Waveforms

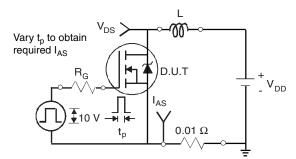


Fig. 14 - Unclamped Inductive Test Circuit

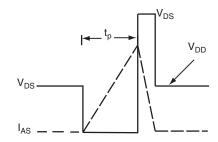


Fig. 15 - Unclamped Inductive Waveforms

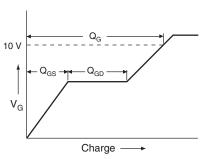


Fig. 16 - Basic Gate Charge Waveform

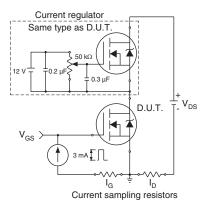
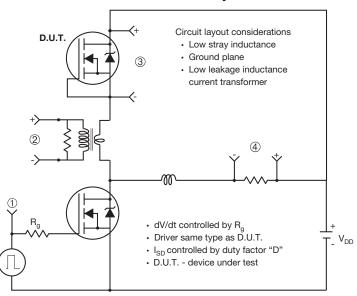


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



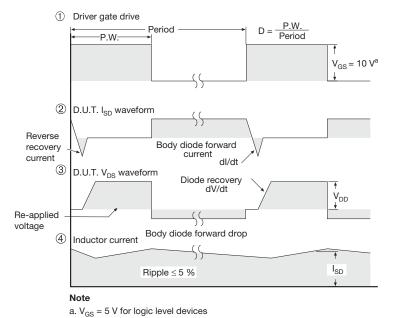
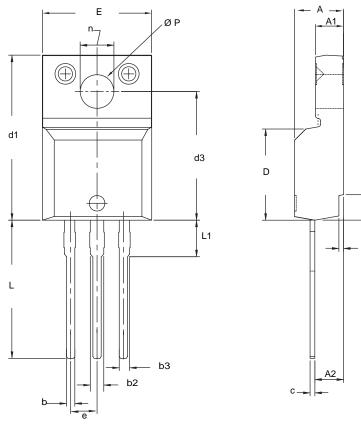


Fig. 18 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**



DIM.	MILLIN	METERS	INCHES	
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.
   No chipping or package damage.



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